U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-1672

SERIAL NO. 09/943,199

LIST OF ART CITED BY APPLICANT

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Kristy A. Campbell, et al. FILING DATE

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	AB	09/732,968		Gilton	1080			12/08/2000	
	AC	09/943,190		Campbell et a FEB 2	6 2002			08/29/2001	
	ΑĹ	09/943,187		Campbell et al				08/29/2001	
	AE	09/779,983		Moore	& TRADE			02/08/2001	
	AF	5,238,862	08/24/93	Bialock et al					
	AG	5,360,981	11/01/94	Owen et al					
	Ан	5,761,115	06/02/98	⊁ozicki et al.					
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	AS	Hirose, et al, "Pol	arity-dependent m	emory switching and behavior of A	ng dendrite in Ag-photodope	d amorphous As	s _z S ₃ films", Jour	nal of Applied	Physics.
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Kristy A. Campbell, et al.

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	AD	4,4	105,710	09/20/83	Balas	subramanyam e	et al.	430	311		
	AE	4,4	119,421	12/06/83	Wilch	helhaus et al.		429	191		
	AF	4,4	199,557	02/12/85	Holm	nberg et al.		365	163		
	AG	5,3	315,131	05/24/94	Kishi	imoto et al.		257	57		
	АН	5,3	350,484	09/27/94	Gard	iner et al.		156	628		
	AI	5.5	512,328	04/30/96	Yosh	nimura et al.		427	498		
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	AB	6,117,720	09/12/00	Harshfield		438	238		
	AC	6,143,604	11/07/00	Chiang et al.		438	253		
	AD	6,177,338 B1	01/23/01	Liaw et al.		438	629		
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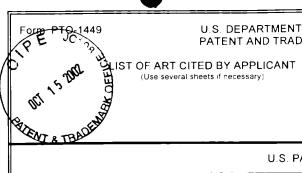
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APPLICANT: Kristy A. Campbell et al.

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	AB	3,743,847	07/03/73	Boland	250	510	:3	·
	AC	4,269,935	05/26/81	Masters et al.	430	323	C.	
	AD	4,312,938	01/26/82	Drexier et al.	430	496		·
	AE	4,320,191	03/16/82	Yoshikawa et al.	430	296		
	AF	4,795,657	01/03/89	Formigoni et al.	427	96		
	AG	4,847,674	07/11/89	Silwa et al.	357	67		
	АН	5,177,567	01/05/93	Klersy et al.	257	4		
	AI	5,219,788	06/15/93	Abernathey et al.	437	187		
\downarrow	AJ	5,726,083	03/10/98	Takaishi	438	210	T	
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ρV	AN	Das et al.,	Theory of the	characteristic curves of the sil-	ver chalcogeni	de glass i	norganic	
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	АВ	5,841,150	11/24/98	Gonzalez et al.	25	7 3		
	AC	5,920,788	07/06/99	Reinberg	43	3 466		
	AD	5,998,066	12/07/99	Block et al.	43	5		
	AE	6,077,729	06/20/00	Harshfield	43	3 128		,
	AF	6,236,059 B1	05/22/01	Wolstenholme et al	. 25	7 3	E.	.) <u>T</u>
	AG	6,297,170 B1	10/02/01	Gabriel et al.	43	3 738		7
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000001				Application Number	09/943,199
INF	ORMATI	ON DISC	CLOSURE	Filing Date	August 29, 2001
STA	TEMEN	T BY AP	PLICANT	First Named Inventor	Kristy A. Campbell
.				Art Unit	2818
	(use as mar	ny sheets as nec	essary)	Examiner Name	David Vu
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